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🔗 [Neuromorphic Device Lab](#)

Biography

Dr. Ang obtained both his B. Eng. (hons) and Ph.D. degrees in electrical engineering from the National University of Singapore. He joined the School of Electrical and Electronic Engineering, Nanyang Technological University in July 2002 as an assistant professor and was promoted to associate professor in April 2008. Dr. Ang's research interests lie mainly in novel semiconductor devices for advanced memory technologies and neuromorphic (non von Neumann) computing and CMOS reliability physics (NBTI, HCI, and TDDDB). Together with his Ph.D. student Ms. Ong Yi Ching, their work on the application of scanning probe techniques to study electronic trap generation in high-k gate dielectrics won them the Bronze prize in the 3rd TSMC Outstanding Student Research Award (under the category of Physics, Chemistry of Material for Nano-Scale Devices). In 2017, his joint work with Mr. Tomohito Kawashima from Toshiba won the first prize of the Best Posters Competition of the China Semiconductor Technology International Conference. Dr. Ang was invited to serve on the technical program committees of the IEEE International Reliability Physics Symposium (2004-2006, 2013), International IEEE International Integrated Reliability Workshop (2009-2013) and IEEE International Symposium on the Physical and Failure Analysis of Integrated Circuits (2004-2015). He also served as a member of the editorial board of the Open Electrical and Electronic Engineering Journal from 2007-2016 and as a guest editor for a topical volume on neuromorphic engineering for Frontiers in Neuroscience.